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| Notice of References Cited | Application/Control No. 09/983,041 | Applicant(s)/Patent Under Reexamination SHIBUYA, ATSUSHI | |
| | Examiner Hai V. Nguyen | Art Unit 2142 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-5,948,058 | 09-1999 | Kudoh et al. | 709/206 |
| * | B | US-6,505,195 | 01-2003 | Ikeda et al. | 707/3 |
| * | C | US-6,973,458 | 12-2005 | Maeda et al. | 707/101 |
| * | D | US-7,031,965 | 04-2006 | Moriya et al. | 707/10 |
| * | E | US-2002/0149611 | 10-2002 | May, Julian S. | 345/706 |
| * | F | US-2002/0194006 | 12-2002 | Challapali, Kiran | 704/276 |
| * | G | US-2003/0158734 | 08-2003 | CRUICKSHANK, BRIAN | 704/260 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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